



Edition 4.0 2023-06 COMMENTED VERSION

# INTERNATIONAL STANDARD



# Photovoltaic devices – Part 2: Requirements for photovoltaic reference devices

<u>IEC 60904-2:2023</u> https://standards.iteh.ai/catalog/standards/sist/73861c07-b6d4-440b-8190-233fadb531a0/iec-60904-2-2023





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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ICS 27.160

ISBN 978-2-8322-7145-2

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#### INTERNATIONAL ELECTROTECHNICAL COMMISSION

## PHOTOVOLTAIC DEVICES -

### Part 2: Requirements for photovoltaic reference devices

### FOREWORD

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This commented version (CMV) of the official standard IEC 60904-2:2023 edition 4.0 allows the user to identify the changes made to the previous IEC 60904-2:2015 edition 3.0. Furthermore, comments from IEC TC 82 experts are provided to explain the reasons of the most relevant changes, or to clarify any part of the content.

A vertical bar appears in the margin wherever a change has been made. Additions are in green text, deletions are in strikethrough red text. Experts' comments are identified by a blue-background number. Mouse over a number to display a pop-up note with the comment.

This publication contains the CMV and the official standard. The full list of comments is available at the end of the CMV.

IEC 60904-2 has been prepared by IEC technical committee 82: Solar photovoltaic energy systems. It is an International Standard.

This fourth edition cancels and replaces the third edition published in 2015. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) added calibration procedures for calibrating PV devices at maximum power by extending the respective Clauses 12 and 13;
- revised requirements for mandatory measurement of spectral responsivity, temperature coefficients and linearity, depending on usage and allowing some measurements on equivalent devices;
- c) revised requirements for built-in shunt resistor;
- d) added requirements for traceability of calibration explicitly.

The text of this International Standard is based on the following documents:

Draft	Report on voting
82/2127/FDIS	82/2151/RVD

Full information on the voting for its approval can be found in the report on voting indicated in the above table.

## standards.iteh.ai)

The language used for the development of this International Standard is English.

This document was drafted in accordance with ISO/IEC Directives, Part 2, and developed in accordance with ISO/IEC Directives, Part 1 and ISO/IEC Directives, IEC Supplement, available at www.iec.ch/members\_experts/refdocs. The main document types developed by IEC are described in greater detail at www.iec.ch/publications.

A list of all parts in the IEC 60904 series, published under the general title *Photovoltaic devices*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under webstore.iec.ch in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

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# PHOTOVOLTAIC DEVICES -

### Part 2: Requirements for photovoltaic reference devices

#### 1 Scope

This part of IEC 60904 gives requirements for the classification, selection, packaging, marking, calibration and care of photovoltaic reference devices.

This document-covers applies to photovoltaic (PV) reference devices that are used to-determine measure the irradiance of natural or simulated sunlight for the purpose of quantifying the electrical performance of photovoltaic devices (cells, modules and arrays-under natural and simulated sunlight). It does not cover photovoltaic reference devices for use under concentrated sunlight.

#### 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60891, Photovoltaic devices – Procedures for temperature and irradiance corrections to measured *I-V* characteristics

IEC 60904-2:2023

IEC 60904-1, Photovoltaic devices – Part 1: Measurement of photovoltaic current-voltage characteristics

IEC 60904-3, Photovoltaic devices – Part 3: Measurement principles for terrestrial photovoltaic (PV) solar devices with reference spectral irradiance data

IEC 60904-4, *Photovoltaic devices – Part 4:* Reference solar *Photovoltaic reference devices – Procedures for establishing calibration traceability* 

IEC 60904-5, Photovoltaic devices – Part 5: Determination of the equivalent cell temperature *(ECT)* of photovoltaic *(PV)* devices by the open-circuit voltage method

IEC 60904-7, *Photovoltaic devices – Part 7: Computation of the spectral mismatch correction for measurements of photovoltaic devices* 

IEC 60904-8, Photovoltaic devices – Part 8: Measurement of spectral responsivity of a photovoltaic (PV) device

IEC 60904-9, *Photovoltaic devices – Part 9: Classification of solar simulator-performance* requirements characteristics

IEC 60904-10, Photovoltaic devices – Part 10: Methods of linear dependence and linearity measurements

IEC TS 61836, Solar photovoltaic energy systems – Terms, definitions and symbols

#### 3 Terms and definitions

For the purposes of this document, the terms and definitions given in IEC TS 61836 and the following apply.

ISO and IEC maintain terminology databases for use in standardization at the following addresses:

- IEC Electropedia: available at https://www.electropedia.org/
- ISO Online browsing platform: available at https://www.iso.org/obp

#### 3.1

#### calibration traceability

#### traceability as defined in IEC 60904-4

<of a PV reference device> requirement for any PV reference device, to tie its calibration value
to SI units in an unbroken and documented chain of calibration transfers including stated
uncertainties 1

Note 1 to entry: Photovoltaic reference devices are distinguished by their position in a chain of calibration traceability.

[SOURCE IEC 60904-4:2019, 3.6, modified – The term "traceability" has been replaced with "calibration traceability" and Note 1 to entry has been replaced.]

#### 3.2

#### reference device

specially calibrated photovoltaic devices which are used to measure natural or simulated irradiance or to set simulator irradiance levels for measuring the performance of other photovoltaic devices

traceably calibrated photovoltaic device/sist/73861c07-b6d4-440b-8190-233fadb531a0/iec-

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Note 1 to entry: Normally used to measure natural or simulated solar irradiance or to set solar simulator irradiance levels for measuring the performance of other photovoltaic devices. 2

#### 3.3

#### primary reference device

photovoltaic reference device-whose calibration is based on a radiometer or standard detector or standard light source with calibration based on a secondary standard for irradiance **3** traceable to SI units as defined in IEC 60904-4

Note 1 to entry: Typically, a PV cell is used as a reference device for the measurement of natural or simulated solar irradiance.

Note 2 to entry: Primary references are normally used by calibration and testing laboratories to calibrate secondary references.

Note 3 to entry: Normally calibrated at periodic intervals. 4

#### 3.4

#### secondary reference device

photovoltaic reference device calibrated in natural or simulated sunlight against a primary reference device

Note 1 to entry: Secondary references are normally used by calibration and testing laboratories to calibrate working references, but also for daily routine measurements, in industrial production and in monitoring.

Note 2 to entry: Normally calibrated at periodic intervals. 5

#### 3.5

#### working reference device

photovoltaic reference device calibrated in natural or simulated sunlight against a secondary reference device

Note 1 to entry: Working references are normally used for daily routine measurements, in industrial production and in monitoring.

Note 2 to entry: Normally calibrated at periodic intervals. 6

#### 3.6 reference cell single photovoltaic cell used primarily for transfer of calibration values

reference device consisting of a single photovoltaic cell **7** 

Note 1 to entry: For practical reasons, such cells are small in surface area, and are usually mounted on a fixture which ensures reproducibility in mounting, thermal control, electrical connections and protects the device. A typical sample is sketched in Figure 1.

Note 2 to entry: Normally the reference cells are also provided with a protective window and embedded in an encapsulant.

Note 3 to entry: Recommended use: as a laboratory primary, secondary and working reference.

Note 4 to entry: If the encapsulation system has been demonstrated to withstand long-term outdoor exposure, applying test levels according to the IEC 61215 series [1], such reference cells can also be suitable to be used as a monitoring device for long-term assessment of operational PV arrays.

Note 5 to entry: If the reference cell is provided with a protective window but without encapsulant, then it should only be used when measuring the performance of other PV devices using direct beam natural or simulated sunlight. 8

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#### **3.6.1**

reference cell with protective cover but without encapsulant photovoltaic reference cell similar to 3.6, but provided with a protective cover

Note 1 to entry: Recommended use: as a laboratory primary, secondary and working reference, in particular when measuring the performance of other photovoltaic devices using solar simulators or natural sunlight with direct beam only. 9

#### <del>3.6.2</del>

#### encapsulated reference cell

photovoltaic reference cell similar to 3.6, but encapsulated in a protective assembly so as to withstand short-term outdoor exposure

Note 1 to entry: Recommended use: as a laboratory primary, secondary and working reference, in particular when measurements of the performance of other photovoltaic devices under natural sunlight are performed.

Note 2 to entry: If the encapsulation system has been demonstrated to withstand long term outdoor exposure, applying test levels according to IEC 61215, such reference cells may also be suitable to be used as a monitoring device for long term accessment of operational photovoltaic arrays. **10** 

#### <del>3.7</del>

#### multi-cell reference devices

photovoltaic device consisting of several photovoltaic cells

Note 1 to entry: Recommended use: as the diffuse component of natural sunlight and non-normal incidence of simulated sunlight interact with encapsulants and back sheets of a module and influence the amount of irradiance which a particular cell receives, it is recommended that reference devices used for measuring sub-assemblies of modules and arrays be encapsulated in a multi-cell package, matching the mechanical and optical features of the test specimen (module, sub-assemblies of modules, arrays) so as to respond to variations in the geometrical distribution of the incident radiation in the same way as the test specimen. **11** 

#### 3.7

#### single reference cell in a multi-cell package

reference device consisting of a single photovoltaic cell mounted in a package such that frame, encapsulation system, shape, size and spacing of the cells surrounding it are the same as in the PV module to be tested

Note 1 to entry: The surrounding cells may be real or dummies that have the same optical properties.

#### 3.8

#### reference module

photovoltaic module consisting of the encapsulation of a series and/or parallel connection of photovoltaic cells

reference device consisting of a photovoltaic module **12** 

Note 1 to entry: Recommended use: for measuring other modules in order to achieve correspondence of dimensions, mechanical construction, optical properties and electrical circuitry of the reference module and test module, so as to minimize discrepancies due to solar simulator spatial non-uniformity, internal reflections-or, temperature distribution and spectral mismatch.

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Note 2 to entry: As the diffuse component of natural sunlight and non-normal incidence of simulated sunlight interact with encapsulants and back sheets of a PV module and influence the amount of irradiance which a particular cell receives, it is recommended that reference devices used for measuring PV modules, sub-assemblies of PV modules and PV arrays be encapsulated matching the mechanical and optical features of the device under test. **13** 

#### 3.9

#### built-in shunt resistor

resistor connected across the output terminals of photovoltaic devices including connection wiring

Note 1 to entry: The resistor shunts the output of the photovoltaic device providing an output voltage to be measured and avoiding user-provided means of establishing short-circuit condition.

Note 2 to entry: For details consult 4.4.

#### 4 Selection of reference device

#### 4.1 General requirements

Depending on their intended use, reference devices need to meet different requirements in terms of their spectral responsivity, mechanical construction, optical properties, dimensions and electrical circuit. The spectral responsivity of the reference device, for example, is determined by the transmission of any protective <u>cover</u> window in front of the device and the spectral responsivity of the device itself. Therefore, the overall spectral responsivity can be adapted by using suitable filters as or in addition to the protective <u>cover</u> window.

A reference device shall meet the following requirements:

a) photovoltaic characteristics shall be stable according to the requirements in Clause 11;

# b) the output signal of the reference device shall vary linearly with irradiance, as defined in IEC 60904-10, over the range of interest. 14

Reference devices should be made using a PV technology that is known to be stable with time. In particular, the calibration value should not change after the reference device has been exposed to solar irradiation, device temperatures different from its calibration temperature and/or extended storage in the dark. The photovoltaic characteristics of a reference device shall be stable according to the requirements in Clause 11. **15** 

The reference device shall be constructed such that the photovoltaic performance parameters, in particular short-circuit current and maximum power, can be measured. The only exception are devices with a built-in shunt resistor, see 4.4.

#### 4.2 Additional requirements for single reference cell in a multi-cell package

The dotted line in Figure 2 indicates the minimum acceptable size of a multi-cell package. For other cell arrangements, such as half-cut cells, an analogous configuration applies.



Figure 2 – Single reference cell in a multi-cell package

#### 4.3 Additional requirements for reference modules

Additional requirements apply to reference modules.

- a) Bypass diodes:
  - general reference modules, which are used to measure a range of module types and geometries, should not contain bypass diodes. The presence or absence of bypass diodes shall be noted and considered in conjunction with the measurement conditions, in particular spatial non-uniformity of the irradiance on the module during measurement;
  - for reference modules, which are intended to be matched to the module under test, the number, type and connection of bypass diodes (if present) shall match those in the module under test.
- b) If they are made from discrete cells, these-shall should **16** be matched as follows depending on the intended use of the reference module:
  - if only the short-circuit current of the reference module will be used, the short-circuit current of the individual cells-shall should **17** be matched to within ±1 %;
  - if other parameters (such as maximum power) are used additionally or exclusively, both the short-circuit current and the fill factor of the individual cells-shall should 18 be matched to within ±1 %.

The matching of the individual cells is the responsibility of the manufacturer of the reference module, bearing in mind that matching <u>may</u> can also be influenced by encapsulation or lamination. The cell matching need not be checked by the calibration laboratory. However, if *I*-*V* curves of the reference module indicate inconsistent response (i.e. obvious steps are noted in the *I*-*V* curve), the I-V curve should be measured under light that is known to be uniform (e.g. natural sunlight) to determine whether there is evidence that the cells within the module are matched within 1 % this should be discussed between calibration laboratory and the client supplying the module before proceeding with calibration. If the module exhibits evidence of > 1 % mismatch between cells, the module shall not be used as reference module.

#### 4.4 Requirements for built-in shunt resistors

The built-in shunt resistor (see 3.9)-shall should **20** be chosen such as to ensure that the reference device operates sufficiently near to short-circuit condition, meeting the requirement in Formula (1):

 $I_{SC} \times R_{CAL} < 0.03 \times V_{OC}$ 

$$R_{\text{CAL}} < \frac{0.2 \times V_{\text{OC}}}{I_{\text{SC}}}$$

(1)

#### where

*R*<sub>CAI</sub> is the built-in shunt resistor;

 $I_{\rm SC}$  is the short-circuit current of the reference device at desired reference conditions;

 $V_{OC}$  is the open circuit voltage of the reference device at desired reference conditions.

If a shunted reference cell does not meet the requirement of formula (1), it shall only be used at irradiances ( $\pm$  5 %) and temperatures ( $\pm$  2 °C) at which it was calibrated. 21

The long-term stability of <u>such resistors</u> the built-in shunt resistor shall also meet the stability requirements of the reference device. Calibration values of such reference devices shall be measured as the voltage drop across the built-in shunt resistor and stated with the dimension [V]-at standard test conditions (see Clause 7). The temperature coefficient of the built-in shunt resistor is part of the temperature coefficient of the calibration value of the reference device. As the uncertainty in the calibration-may can be strongly dependent on the built-in shunt resistor stability and temperature coefficient, respective values should be provided with the reference cell data sheet.

If a shunted reference cell is to be used for low irradiance measurements, either a dedicated cell can be constructed with the restriction of formula (1), where the short circuit current is considered at the desired low irradiance rather than at STC. Alternatively a shunted cell can have a larger shunt resistor, but requires a separate calibration for each irradiance and temperature it is to be used at. 22

It is recommended that the shunt resistor be a removable 4-wire resistor, to allow for standard (current-based) measurements of spectral responsivity and periodic checking of the reference device stability by-taking measuring an *I-V* curve-per in accordance with IEC 60904-1. However, the reproducibility of the electrical connection shall be maintained.

Formula (1) means that the measured output voltage of a shunted reference cell-shall should be less than 320 % 23 of its open circuit voltage. For typical crystalline silicon this equates to about  $20 \times 20$  mV output.

#### 5 Temperature measurement

Means shall be provided for determining the reference cell temperature or, for reference modules, the equivalent cell temperature (ECT), according to IEC 60904-5. Temperature sensors and instrumentation shall have instrumental measurement uncertainty of 1 °C or less 24. The required uncertainty for temperature measurements for the cell junction shall be less than ± 2,0 °C for all reference devices. A minimum accuracy of ±1,0 °C for the temperature sensor is suggested to achieve this uncertainty in the temperature measurement.

#### **Electrical connections** 6

The electrical connections to reference cells without built-in shunt resistor shall consist of a four-wire contact system (Kelvin probe). Care shall be taken to avoid Measurement errors due to voltage drops along the cell's contact bars and the package wiring shall be avoided.

The electrical connections to the reference module shall be designed to meet the requirements of IEC 60904-1.

#### Calibration 7

#### 7.1 **General requirements**

Each calibration of a reference device shall be made with a calibration procedure that is traceable according to IEC 60904-4. Any measurement instrument used in the calibration procedure shall be an instrument with an unbroken traceability chain. 25

The laboratory performing the calibration of the reference device shall maintain a documented uncertainty analysis as well as documented repeatability and results from interlaboratory 

#### 7.2 Calibration value(s)

Each reference device shall be calibrated in terms of its calibration value(s) at the desired reference conditions, normally standard test conditions (STC) (1 000 W·m<sup>-2</sup>, 25 °C device temperature with the reference spectral irradiance distribution as defined in IEC 60904-3). Calibration values shall be reported together with the three main parameters of total irradiance, device junction temperature and spectral irradiance. The most common calibration conditions are standard test conditions (STC). A calibration at STC shall refer to a total irradiance of 1 000 W m<sup>-2</sup>, a device junction temperature of 25 °C and the reference spectral irradiance distribution as defined in IEC 60904-3. Sometimes calibration is required at other conditions. A reference device can have multiple calibration values for different desired reference conditions. In particular, IEC 61853-1 [2]<sup>1</sup> requires the use of a reference device at a range of irradiances and temperatures and therefore the calibration at the respective conditions. 26

Methods for calibrating primary reference devices are included in IEC 60904-4. A-method procedure of calibrating secondary reference devices is described in Clause 13. The calibration of working reference devices is treated in Clause 14.

#### 7.3 Spectral responsivity

In general, the spectral responsivity at short-circuit current conditions of each reference device shall be measured in accordance with IEC 60904-8. If for reference modules this cannot be measured directly, it shall be deduced from measurements made on representative encapsulated photovoltaic cells. For exceptions related to working references, see Clause 14. 27

<sup>1</sup> Numbers in square brackets refer to the Bibliography.

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#### 7.4 Temperature coefficients

The determination of the temperature coefficient(s) of each reference device shall be measured in accordance with IEC 60891 is in general optional but depending on usage might be mandatory, and in any case is strongly recommended. If the temperature coefficient(s) are determined, also their linear dependence in accordance with IEC 60904-10 shall be reported. For exceptions related to working references, see Clause 14. 28

#### 7.5 Linearity

The determination of linearity in accordance with IEC 60904-10 is in general optional but depending on usage might be mandatory, and in any case is strongly recommended. For exceptions related to working references, see Clause 14. **29** 

#### 8 Documentation and report 30

Each time a reference device is calibrated, the following information shall be recorded on a data sheet:

- Type (primary reference cell; secondary reference device, working reference device)
- Material type
- Type of package

- Type and dimension of cell(s) and and sitten ai)

- Circuit diagram, in particular of any connectors
- Calibration organization IEC 60904-2-

- Site and date of calibration / standards/sist/73861c07-b6d4-440b-8190-233fadb531a0/iec-

- Method of calibration (refer to standard) 04-2-2023
- Primary reference cell identification (where applicable)
- <u>Simulator characteristics (where applicable)</u>
- Type of temperature sensor (where applicable)
- -Spectral responsivity
- Temperature coefficient of calibration value
- Calibration value at reference conditions
- Reference conditions
- Estimated uncertainty
- Shunt resistor nominal resistance and temperature coefficient (where applicable)
- Either the mismatch correction value used in the measurement or an estimate of the uncertainty introduced by using the mismatched reference device.

For reference cells without fixed electrical connection to the cell, the following information shall be recorded on the data sheet:

For reference modules, the following information shall be recorded in addition on the data sheet:

- model designation

- serial number